

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/938,337	SUN ET AL.	
Examiner		Richard Lee	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,256,343 B1	07-2001	Suzuki, Yoshinori	375/240
	B	US-6,055,330 A	04-2000	Eleftheriadis et al.	382/236
	C	US-5,440,345 A	08-1995	Shimoda, Kenji	375/240.14
	D	US-5,657,087	08-1997	Jeong et al.	375/240.16
	E	US-2001/0002922	06-2001	Hayashi, Naoya	375/240.16
	F	US-2003/0174776 A1	09-2003	Shimizu et al.	375/240.16
	G	US-2002/0118761 A1	08-2002	Lee, Sung-Hee	375/240.27
	H	US-6,310,920 B1	10-2001	Ogawa, Yoichi	375/240.17
	I	US-6,023,300 A	02-2000	Han et al.	375/240.16
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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